

TRANSMITTAL OF INFORMATION DISCLOSURE STATEMENT (Under 37 CFR 1.97(b) or 1.97(c))						Docket No. 03100275AA
In Re Application Of: B. Bodermann						
Application No. not yet assigned	Filing Date concurrently	Examiner not yet assigned	Customer No. 30743	Group Art Unit not yet assigned	Confirmation No. not yet assigned	
Title: METHOD FOR DETERMINING THE REFRACTIVE INDEX DURING INTERFEROMETRIC LENGTH MEASUREMENT AND INTERFEROMETRIC ARRANGEMENT THEREFOR						
<p>Address to:</p> <p>Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450</p> <p>37 CFR 1.97(b)</p> <p>1. <input checked="" type="checkbox"/> The Information Disclosure Statement submitted herewith is being filed within three months of the filing of a national application other than a continued prosecution application under 37 CFR 1.53(d); within three months of the date of entry of the national stage as set forth in 37 CFR 1.491 in an international application; before the mailing of a first Office Action on the merits, or before the mailing of a first Office Action after the filing of a request for continued examination under 37 CFR 1.114.</p> <p style="text-align: center;">37 CFR 1.97(c)</p> <p>2. <input type="checkbox"/> The Information Disclosure Statement submitted herewith is being filed after the period specified in 37 CFR 1.97(b), provided that the Information Disclosure Statement is filed before the mailing date of a Final Action under 37 CFR 1.113, a Notice of Allowance under 37 CFR 1.311, or an Action that otherwise closes prosecution in the application, and is accompanied by one of:</p> <p style="margin-left: 40px;"><input type="checkbox"/> the statement specified in 37 CFR 1.97(e);</p> <p style="text-align: center;">OR</p> <p style="margin-left: 40px;"><input type="checkbox"/> the fee set forth in 37 CFR 1.17(p).</p>						

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Title: **METHOD FOR DETERMINING THE REFRACTIVE INDEX DURING INTERFEROMETRIC LENGTH MEASUREMENT AND INTERFEROMETRIC ARRANGEMENT THEREFOR**

Payment of Fee

(Only complete if Applicant elects to pay the fee set forth in 37 CFR 1.17(p))

- ☐ A check in the amount of _____ is attached.
- ☒ The Director is hereby authorized to charge and credit Deposit Account No. 50-2041 as described below.
- ☐ Charge the amount of _____
- ☒ Credit any overpayment.
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- ☐ Payment by credit card. Form PTO-2038 is attached.

WARNING: Information on this form may become public. Credit card information should not be included on this form. Provide credit card information and authorization on PTO-2038.

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(Date)

Signature of Person Mailing Correspondence

Typed or Printed Name of Person Mailing Certificate

*This certificate may only be used if paying by deposit account.

Marshall M. Curtis
Signature

Dated: **January 12, 2006**

Marshall M. Curtis
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703-787-9400
CUSTOMER NUMBER 30743

CC:

10756449

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re patent application of

10756449 23 JAN 2006

B. Bodermann

Serial No.: not yet assigned

Examiner: not yet assigned

Filing Date: Concurrently

Group Art Unit: not yet assigned

For: METHOD FOR DETERMINING THE REFRACTIVE INDEX
DURING INTERFEROMETRIC LENGTH MEASUREMENT
AND INTERFEROMETRIC ARRANGEMENT THEREFOR

Commissioner for Patents
PO Box 1450
Alexandria, Virginia 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

Under the provisions of 37 C.F.R. 1.97 through 1.99 and pursuant to applicant's duty of disclosure under 37 C.F.R. 1.56, applicant respectfully brings the following documents, listed on the attached form PTO-1449, to the attention of the Examiner in charge of the above-identified application.

These citations do not constitute an admission that the references are relevant or material to the claims. They are only cited as constituting related art of which the applicant is aware.

It is respectfully requested that the listed references be considered by the Examiner and formally made of record in this application. Please charge any deficiencies in fees and credit any overpayment of fees to attorney's Deposit Account No. 50-2041.

Respectfully submitted,



Marshall M. Curtis
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Customer No. 30743

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /PC/

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>				ATTY DOCKET NO.		APPLICATION NO.	
				03100275AA		107554479	
				APPLICANT(S)		not yet assigned	
				B. Boermann		12 JAN 2006	
FILING DATE				GROUP ART UNIT			
concurrently				not yet assigned			

U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	6417927	7/2002	de Groot			
	3877813	4/1975	Hayes et al.			
	5838485	11/1998	de Groot et al.			
	5764362	6/1998	Hill et al.			
	5404222	4/1995	Lis			

U.S. PATENT APPLICATION PUBLICATIONS						
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	2002/0001086	1/2002	De Groot			

FOREIGN PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
	2346967	8/2000	United Kingdom			✓	
	19727402	2/1998	Germany				✓
	19727404	2/1998	Germany				✓
	WO99/42787	8/1999	International			✓	

OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>			
			G. Bonsch et al., "Measurement of the Refractive Index of Air and Comparison with Modified Edlen's Formulae"; Metrologia, 1998 Vol. 35, PP 133-139.
			B. Boermann et al., "Improved Second Harmonic Two Wavelength Interferometer with Refractive Index Correction without Effect Modulation"; Proc. of SPIE, Vol. 5190, 2003; pp. 339-346.

EXAMINER /Patrick Connolly/ (05/21/2008)	DATE CONSIDERED
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH PAGE /PC/ OF